

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Serial No.:	10/736,386	)	
		)	
Filed:	December 15, 2003	)	Conf. No.: 6227
		)	
Title:	<b>METHOD FOR CALCULATING</b>	)	
	<b>HIGH-RESOLUTION WAFER</b>	)	
	<b>PARAMETER PROFILES</b>	)	
		)	
Inventors:	Bruce Whitefield et al.	)	
		)	
Art Unit:	2128	)	
		)	
Examiner:	Hugh M. Jones	)	
		)	
Atty. Ref:	03-1345	)	

**RESPONSE TO THE OFFICE ACTION MAILED OCTOBER 20, 2008**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed October 20, 2008, kindly consider the following remarks toward reconsideration of the present application.